



(11) **EP 1 686 509 A3**

(12) **EUROPEAN PATENT APPLICATION**

(88) Date of publication A3:
29.06.2011 Bulletin 2011/26

(51) Int Cl.:
G06K 9/62 ^(2006.01) **G06K 9/00** ^(2006.01)
G01N 21/00 ^(2006.01)

(43) Date of publication A2:
02.08.2006 Bulletin 2006/31

(21) Application number: **05109975.2**

(22) Date of filing: **25.10.2005**

(84) Designated Contracting States:
AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IS IT LI LT LU LV MC NL PL PT RO SE SI SK TR
Designated Extension States:
AL BA HR MK YU

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(30) Priority: **25.10.2004 JP 2004309447**

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(54) **Mapping-data analyzing method and apparatus**

(57) It is an object of the present invention to provide a mapping-data analyzing method that can display a map in which sufficient information is extracted from the spectra of obtained mapping data to enable objective analysis. The mapping-data analyzing method of the present invention is used for analyzing mapping data obtained by measuring, with a spectrometer apparatus, spectra at a plurality of points on a specimen surface. The method comprises a principal-component calculating step and a grouped-map display step. In the principal-component calculating step, spectral data obtained at each point on the specimen surface is defined as an individual sample

and principal component analysis, in which values at a plurality of wavenumbers of each spectral data set serve as variables, is performed to calculate the scores of a plurality of principal components for each individual sample. In the grouped-map display step, the points on the specimen surface are divided into a plurality of groups based on the scores of a plurality of principal components calculated in the principal-component calculating step and a two-dimensional or three-dimensional map indicating to which group each point on the specimen surface belongs is displayed on a display device.



EUROPEAN SEARCH REPORT

Application Number
EP 05 10 9975

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (IPC)
X	<p>"Chapter 8 : Visualization in Score Plots" In: Paul Geladi et al: "Multivariate Image Analysis", 1 January 1996 (1996-01-01), Wiley, XP008135371, ISBN: 978-0-471-93001-6 pages 157-173, * page 157, paragraph 1 - paragraph 4; figures 8.4, 8.5 * * page 168, last paragraph - page 171, paragraph 2; figures 8.16-8.18 * -& "Chapter 11 : Miscellaneous Examples" In: Paul Geladi et al: "Multivariate Image Analysis", 1 January 1996 (1996-01-01), Wiley, XP008135373, ISBN: 978-0-471-93001-6 pages 215-233, * page 229, last paragraph - page 233, column 1; figures 11.9-11.19 * -& "Chapter 6 : Principal Component Analysis on Multivariate Images" In: Paul Geladi et al: "Multivariate Image Analysis", 1 January 1996 (1996-01-01), Wiley, XP008135829, ISBN: 978-0-471-93001-3 pages 107-135, * page 109, paragraph 2 - page 110, column 1; figures 6.6, 6.14; table 6.4 * ----- -/--</p>	1-19	<p>INV. G06K9/62 G06K9/00 G01N21/00</p> <hr/> <p>TECHNICAL FIELDS SEARCHED (IPC)</p> <p>G06K</p>
The present search report has been drawn up for all claims			
13	Place of search The Hague	Date of completion of the search 13 May 2011	Examiner Granger, Bruno
<p>CATEGORY OF CITED DOCUMENTS</p> <p>X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document</p>		<p>T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document</p>	

EPO FORM 1503 03.82 (P04C01)



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X	Jeremy M. Shaver: "Chapter 7 : Chemometrics for Raman Spectroscopy" In: Ian R. Lewis et Howeel G. M. Edwards: "Chapter 7 : Chemometrics for Raman Spectroscopy", 1 January 2001 (2001-01-01), HANDBOOK OF RAMAN SPECTROSCOPY : FROM THE RESEARCH LABORATORY TO THE PROCESS LINE, NEW YORK [U.A.] : MARCEL DEKKER, US, PAGE(S) 275 - 306, XP008135513, ISBN: 0-8247-0557-2 * page 292, paragraph 2 - page 295, last paragraph * * page 275, paragraph 1 - page 277, paragraph 1 * * page 298, paragraph 2 - page 302, paragraph 2 *	1-19	TECHNICAL FIELDS SEARCHED (IPC)
X	Patrick J. Treado et Matthew P. Nelson: "Chapter 5 : Raman Imaging" In: Ian R. Lewis et Howeel G. M. Edwards: "Handbook of Raman Spectroscopy", 1 January 2001 (2001-01-01), Wiley, XP008135514, ISBN: 0-8247-0557-2 pages 191-249, * page 214, paragraph 1 - page 216, paragraph 3; figures 6-23 * * page 230, paragraph 4 * * page 192, paragraph 3 - page 194, paragraph 1; figure 1 * * page 200; figure 5 * * figures 15D, 15E, 22B-D * ----- -/--	1-19	
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EPO FORM 1503 03 82 (P04C01)



EUROPEAN SEARCH REPORT

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T	Zdzislaw Salamon et Gordon Tollin: "Surface Plasmon Resonance, applications" In: John C. Lindon: "Encyclopedia of Spectroscopy and Spectrometry", 1 January 2001 (2001-01-01), Academic Press, XP002635613, pages 2294-2302, * page 2295, left-hand column, paragraph 2 - page 2299, right-hand column, last paragraph *	11-17	TECHNICAL FIELDS SEARCHED (IPC)
T	Zdzislaw Salamon and Gordon Tollin: "Surface Plasmon Resonance, Theory" In: John C. Lindon: "Encyclopedia of Spectroscopy and Spectrometry", 1 January 2000 (2000-01-01), Academic Press, XP002636487, pages 2311-2319, * page 2312, left-hand column, paragraph 1 * * page 2312, right-hand column, paragraph 1 *	11-17	
T	RPH Koyman: "Surface Plasmon Resonance, Instrumentation" In: John C. Lindon: "Encyclopedia of Spectroscopy and Spectrometry", 1 January 2000 (2000-01-01), Academic Press, XP002636488, pages 2302-2310, * page 2304, left-hand column, paragraph 1 * ----- -/--	11-17	
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EPO FORM 1503 03.82 (POAC01)



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T	"Chapter 3: Spectral Analysis" In: B. Stuart: "Infrared Spectroscopy : fundamentals and Applications", 1 January 2004 (2004-01-01), Wiley, XP002634053, ISBN: 0-470-85427-8 pages 45-70, * equation (3.1); paragraph [0003] *	8-10	TECHNICAL FIELDS SEARCHED (IPC)
T	"Chapter 11 : Evaluating" In: Siegfried Wartewig: "IR and Raman Spectroscopy: Fundamental Processing", 1 January 2003 (2003-01-01), Wiley, XP002634054, ISBN: 3-527-30245-X pages 125-158, * page 154 *	4-7	
T	Freek D. van der Meer: "Pixel-based, Stratified and Contextual Analysis of Hyperspectral Imagery" In: Steven M. de Jong et al.: "Remote Sensing Image Analysis", 1 January 2004 (2004-01-01), Kluwer, XP002636778, pages 153-180, * page 155, paragraph 2 - page 172, last paragraph *	4-7,11, 13,14	
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EPO FORM 1503 03.02 (P04C01)